



Metrics NA TC Chapter Meeting Summary and Minutes

SEMICON West
1:00-3:00 PM Pacific
Thursday, October 9, 2025
Phoenix, Arizona

TC Chapter Announcements

SEMI Winter Meetings

Thursday, February 12, 2026

1:00-3:00 PM Pacific

Online via Web Conference

Table 1 Meeting Attendees

Italics indicate virtual participants

Co-Chairs: David Bouldin (Fab Consulting), Vladimir Kraz (OnFilter), Mark Frankfurth (Cymer)

SEMI Staff: Michelle Sun

<i>Company</i>	<i>Last</i>	<i>First</i>	<i>Company</i>	<i>Last</i>	<i>First</i>
Intel Corporation	Schneider	Paul	SEMI	Sun	Michelle
KLA Corporation	<i>Ganev</i>	<i>Todor</i>	SEMI	Trio	Paul
NAURA	<i>Cao</i>	<i>Clark</i>	SUNY RF (Albany)	<i>Eisenbraun</i>	<i>Eric</i>
OnFilter	Kraz	Vladimir	Tokyo Electron Ltd.	Mashiro	Supika

Table 2 Leadership Changes

<i>WG/TF/SC/TC Name</i>	<i>Previous Leader</i>	<i>New Leader</i>
None		

Table 3 TC Chapter Structure Changes

<i>Previous WG/TF/SC Name</i>	<i>New WG/TF/SC Name or Status Change</i>
None	

Table 4 Ballot Results

<i>Document #</i>	<i>Document Title</i>	<i>Committee Action</i>
None		

#1 **Passed** ballots and line items will be submitted to the ISC Audit & Review Subcommittee for procedural review.

#2 **Failed** ballots and line items were returned to the originating task forces for re-work and re-balloting or abandoning.



Table 5 Ratification Ballot Results

<i>Document #</i>	<i>Document Title</i>	<i>ISC A&R Action</i>	<i>A&R Forms</i>
None			

Note 1: **Passed** Ratification ballots will be submitted to SEMI publication for final processing.

Note 2: **Failed** Ratification ballots were returned to the originating task forces for re-work and re-balloting or abandoning.

Table 6 Activities Approved by the GCS between meetings of the TC Chapter

<i>#</i>	<i>Type</i>	<i>SC/TF/WG</i>	<i>Details</i>
None			

Table 7 Authorized Activities

Listing of all revised or new SNARF(s) approved by the Originating TC Chapter.

<i>#</i>	<i>Type</i>	<i>SC/TF/WG</i>	<i>Details</i>
None			

#1 SNARFs and TFOFs are available for review on the SEMI Web site at:

<http://downloads.semi.org/web/wstdsbal.nsf/TFOFSNARF>

Table 8 Authorized Ballots

<i>#</i>	<i>When</i>	<i>TF</i>	<i>Details</i>
7436	Cycle 9-2025	CCC TF	Reapproval of SEMI E180-1220 - Test Method for Measuring Surface Metal Contamination Through ICP-MS of Critical Chamber Components Used in Semiconductor Wafer Processing

Table 9 SNARF(s) Granted a One-Year Extension

<i>#</i>	<i>TF</i>	<i>Title</i>	<i>Expiration Date</i>
6931	CCC TF	New Standard: Test Method for Measuring Organics Contamination Through Thermal Desorption or Solvent Extraction Gas Chromatography Mass Spectrometry of Critical Chamber Components Used in Semiconductor Wafer Processing and Inspection	10/09/2026

Table 10 SNARF(s) Cancelled

<i>#</i>	<i>TF</i>	<i>Title</i>
None		

Table 11 Standard(s) to receive Inactive Status

<i>Standard Designation</i>	<i>Title</i>
None	

Table 12 New Action Items

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
None		



Table 13 Previous Meeting Action Items

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
None		

1 Welcome, Reminders, and Introductions

Vladimir Kraz (OnFilter) called the meeting to order at 1:10. The meeting reminders on antitrust issues, intellectual property issues and holding meetings with international attendance were reviewed. Attendees introduced themselves.

Attachment: Required Meeting Elements March 2024

2 Review of Previous Meeting Minutes

The TC Chapter reviewed the minutes of the previous meeting.

Motion: Approve the minutes as written
By / 2nd: By: Supika Mashiro / Tokyo Electron Ltd.
Second: Paul Schneider / Intel Corporation
Discussion: None
Vote: 5-Y 0-N. Motion passed.

Attachment: Metrics-Minutes-June-2025

3 Liaison Reports

3.1 Metrics Japan TC Chapter

Michelle Sun (SEMI) reported for the Metrics Japan TC Chapter. Of note:

- Meeting Information
 - Last meeting
 - Wednesday, December 11, 2024, in conjunction with SEMICON Japan 2024
 - Tokyo Big Sight, Tokyo, Japan/ OVTCCM (Hybrid)
 - Next meeting
 - Thursday, December 18, 2025, in conjunction with SEMICON Japan 2025
 - TFT Building, Tokyo, Japan/ OVTCCM (Hybrid)
- Organization Chart
 - Int’l Environmental Contamination Control TF - Disbanded by GCS approval as of 2024/11/07

Attachment: 20250926_MetricsJapan_Liaison_Report_R0

3.2 SEMI Staff Report

Michelle Sun (SEMI) gave the SEMI Staff Report. Of note:

- 2025 & 2026 Calendar of Events



Event Name	Event Details
SEMICON® WEST	Oct 07-09, 2025 Phoenix, Arizona
SEMICON® EUROPA	Nov 18-21, 2025 Munich, Germany
SEMICON® JAPAN	Dec 17-19, 2025 Tokyo, Japan
SEMICON® KOREA	Feb 11-13, 2026 Seoul, Korea
SEMICON® CHINA	March 25-27, 2026 Shanghai, China
SEMICON® SOUTHEAST ASIA	May 05-07, 2026 Kuala Lumpur, Malaysia

- SEMICON West 2025-2030

- o 2025—October 7-9 | Phoenix Convention Center | Phoenix, AZ
- o 2026—October 13-15 | Moscone Center | San Francisco, CA
- o 2027—October 12-14 | Phoenix Convention Center | Phoenix, AZ
- o 2028—October 10-12 | Moscone Center | San Francisco, CA
- o 2029—October 9-11 | Phoenix Convention Center | Phoenix, AZ
- o 2030—October 29-31 | Moscone Center | San Francisco, CA

- SEMI Global Standards Summit (GSS) 2025

- o **Date/Time:** Tuesday, October 7 | 1:30 PM to 5:30 PM | North Building, 200 Level, Room 229A
- o **Theme:** Future Standards for Connected & Sustainable Semiconductor Manufacturing
- o **Session Description:** The Global Standards Summit is a strategic forum dedicated to identifying standards-critical areas and advancing an industry-wide standardization roadmap for the next 3- and 7-year horizons. Building on the momentum of the inaugural Summit—which spotlighted essential topics such as environmental sustainability—this year’s gathering continues that dialogue while expanding focus to include emerging challenges like supply chain traceability.
- o With increasing fragmentation across the global microelectronics supply chain driven by geopolitical and other disruptive forces, the need for unified standards is more critical than ever. This Summit provides a timely opportunity to convene, collaborate, and identify the standards that will address these challenges and foster greater industry alignment. We encourage you to join, engage, and help shape the future of standards.

- Workshops

- o SEMI Liquid Chemicals Analytical Workshop
 - Description: Focusing on recent advances in analytical methodology and instrumentation
 - Wednesday, October 8
 - 09:00-11:30 (North Bldg | Room 229B)
- o Enhancing Voltage Sag Immunity: SEMI F47 Standard Updates & Insights
 - Description: Delivering practical recommendations to enhance the SEMI F47 standard and increase tool resilience in future designs, with a focus on power quality conditions, equipment susceptibility, testing approaches, and mitigation strategies.
 - Wednesday, October 8
 - 14:30-16:30 (North Bldg | Room 229B)
- o Semiconductor Device Manufacturing in a Cleanroom (Best Practices to Improve Product Reliability and Yield) [SEMIU]
 - Description: Provides the fundamentals and thought processes to improve your production reliability & yield.
 - Thursday, October 9
 - 8:00 AM - 4:00 PM (North Bldg | 200 Level)

- Upcoming NA Meetings 2026



Event Name	Date/Venue
NA Winter Meeting	Feb 9-12, 2026 Full Virtual
NA Spring Meeting (In conjunction with ASMC)	May 11-14, 2026 Hilton Albany, New York
SEMICON West Meeting	October 12-15, 2026 San Francisco, California/USA

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- SEMI Advanced Semiconductor Manufacturing Conference (ASMC)
 - SEMI's international technical conference for discussing solutions that improve the collective manufacturing expertise of the semiconductor industry.
 - Provides a platform for semiconductor professionals to network and learn the latest in the practical application of advanced manufacturing strategies and methodologies.
- Critical Dates for SEMI Standards Ballots 2026

2026	Ballot Submission Deadline	Voting Opens	Voting Closes
Cycle 1	December 16, 2025	January 7	February 6
Cycle 2	January 23	February 11	March 13
Cycle 3	March 5	March 18	April 17
Cycle 4	March 30	April 14	May 14
Cycle 5	May 8	May 27	June 26
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- SEMI Standards Publications
 - Total Standards: 1,107
 - New Standards

Cycle	Designation	Title	Committee	Region
June 2025	SEMI M94	Specification for Silicon Carbide Engineered Substrates	Compound Semiconductor Materials	EU
July 2025	SEMI E194	Guide to Using a Liquid Particle Counter to Assess Particulate Surface Contamination on Critical Chamber Components and Coupons	Metrics	NA
September 2025	SEMI E195	Test Method Using Adhesive Replacement Substrates to Assess Particulate Surface Contamination on Critical Chamber Components	Metrics	NA
September 2025	SEMI E196	Guide for Equipment Edge Data Governance	Information & Control	TW
September 2025	SEMI M95	Test Method for Net Carrier Density and Resistivity of Silicon Epitaxial Layer by Capacitance-Voltage Measurements with an Evaporated Metal Schottky Diode	Silicon Wafer	JP
September 2025	SEMI T26	Specification for Electronic Supply Chain Traceability Using Distributed Ledger Technology	Traceability	NA

- Educational Courses under Development
 - {EDA} Everything You Need to Know about the SEMI Equipment Data Acquisition (EDA) Standards Suite
 - Objective: Introduce EDA standards, best practices for implementation, and addresses concerns about adoption through example use cases



- Course Date: November 20, 2025, in conjunction with SEMICON Europa
- Status: Confirmed, under development
- {Subfab} Intro to Sub-fab Course
 - Objective: Gain a comprehensive understanding of SubFAB operations, including system components, facility layouts, environmental and sustainability considerations, organizational structure, safety and maintenance best practices, and incident-response preparedness within the semiconductor manufacturing ecosystem.
 - Course Date: Early 2026 (2 sessions, EU & Asia friendly)
 - Status: Under development
- Regulations & Procedure Manual
 - Regulations (Feb 20, 2024)
 - <https://www.semi.org/sites/semi.org/files/2024-02/Standards%20Regulations%20February%202024.pdf>
 - Procedure Manual (July 7, 2025)
 - <https://www.semi.org/sites/semi.org/files/2025-07/Procedure%20Manual%20July%202025%20v1.pdf>
 - Noticeable updates:
 - Major revision to multiple Standards
 - New SNARF Form (July 2025)
 - Ballot checklist requirement for Revision to Primary Standard
- SNARF(s) Approved by GCS
 - 7357, New Standard: Specification for Failure Analysis Reporting
 - 7381, Revision to Add a New Subordinate Standard: Specification for Transforming Non-E142 XY Coordinates to SEMI E142-0125: Specification for Substrate Mapping

Attachment: IC_Staff_HQ Report Oct 2025 v5

4 Subcommittee and Task Force Reports

4.1 EMC TF

Vladimir Kraz (OnFilter) reported for the EMC Task Force.

- Industry Update
 - EMC:
 - IEEE EMC Symposium August 18-22 2025, Raleigh, NC
 - EMC Europe September 1-5 Paris
 - European EMC Symposium September 1-5, 2025, Paris
 - ESD:
 - EOS/ESD Association' Standards Meeting, June 2-6, 2025 (now) Riverside, CA
- Intel was not present to share suggestions on gradation of ELF/VLF levels. Task Force agreed to put the activity on hold.

4.2 E-RAMP Task Force

Paul Schneider (Intel) reported for the E-RAMP Task Force.

- Task Force is continuing work on SEMI E10 and E79 webinars.

4.3 CCC Task Force

Supika Mashiro (TEL) reported for the CCC Task Force.

- Task Force is continuing work on New Standard: Test Method for Measuring and Characterizing Surface Particle Contamination on Critical Chamber Components with Airborne Particle Counter and Dry Aerosolizing Chamber



- Overarching document for SEMI E194 - Guide to Using a Liquid Particle Counter to Assess Particulate Surface Contamination on Critical Chamber Components and Coupons and E195 - Test Method Using Adhesive Replacement Substrates to Assess Particulate Surface Contamination on Critical Chamber Components has been delayed.

5 Next Meeting and Adjournment

The next meeting is tentatively scheduled for Thursday, February 12, 2026, from 1:00-3:00 Pacific Time. See <http://www.semi.org/standards-events> for the current list of events.

Adjournment: 2:00.

Respectfully submitted by:

Michelle Sun
 Coordinator
 SEMI North America
 Phone: 408.943.7982
 Email: msun@semi.org

Minutes tentatively approved by:

<Name> (<Company>), Co-chair	<Date approved>
<Name> (<Company>), Co-chair	<Date approved>

Table 14 Index of Available Attachments#1

<i>Title</i>	<i>Title</i>
Metrics-Minutes-June-2025	20250926_MetricsJapan_Liaison_Report_R0
IC_Staff_HQ Report Oct 2025 v5	

#1 Due to file size and delivery issues, attachments must be downloaded separately. A .zip file containing all attachments for these minutes is available at www.semi.org. For additional information or to obtain individual attachments, please contact [SEMI Staff Name] at the contact information above.